

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination YAMAUCHI ET AL.	
		Examiner Kwang Han	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0142430	06-2005	Yoshida et al.	429/044
*	B US-2005/0233203	10-2005	Hampden-Smith et al.	429/044
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	WO 03/081700	10-2003	WIPO	Yoshida et al.	H01M 4/86
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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